



QUANTAX

• EDS with Slim-line Technology for SEM and TEM

The new generation of QUANTAX EDS once more sets the standards in X-ray spectrometry. The XFlash® 6 detector series, combined with the modular ESPRIT software, delivers the fastest and most reliable results in nano-research.



Wide range of detector sizes

 10, 30, 60 and 100 mm² area detectors offer ideal solutions for microanalysis and nano-analysis



Best energy resolution for light element and low energy analysis

- 121 eV limited edition, 123 eV ultimate, 126 eV premium, 129 eV standard
- All resolutions specified exceeding ISO 15632:2002 requirements



Slim-line detector technology for even more counts and lower beam currents

- Shortest detector to sample distances for maximum solid angle for SEM, FIB-SEM, µ-probe and TEM
- Best available take-off angle for TEM

Innovation with Integrity

EDS



The XFlash® 6 detector series for SEM and TEM



Ultra high throughput for fastest measurements

- New signal processing unit with hybrid technology
 - Over 1,500 kcps input count rate
 - Over 600 kcps output count rate



Hybrid quantification

Real-time spectrometry

Instant spectrum visibilityLive quantification

- Unique combination of standardless and standardbased guantification
- Customizable for most accurate quantification



Automation of routines

- Automate virtually any measurement and analysis
- Optimization of instrument usage
- Unattended operation during the day, at night or over the weekend

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Best energy resolution ranges of different detector designs, showing clear advantages for the XFlash® 6

Compact design and low weight

- High precision slider with fully integrated motor for precise positioning
- Improved heat sink geometry for stable measurement conditions
- Maximum detector weight of 3.75 kg

Light element / low energy analysis

- Most comprehensive database containing K, L, M and N element lines for accurate identification
- TQuant optimized standardless low energy range quantification

HyperMap

- The database contains a spectrum for each pixel
- Enables on- and offline processing
- Live background removal and deconvolution

Detector configurations

- Available detectors for SEM and related:
- XFlash[®] 6 | 10 XFlash[®] 6 | 30 XFlash[®] 6 | 60 XFlash[®] 6 | 100

Recommended detectors for TEM:

XFlash® 6T | 30 XFlash® 6T | 60

ESPRIT

Analytical software suite providing options for

- Reliable spectrometry
- Super fast Mapping
- High resolution Imaging
- Combined EBSD
- Easy automation
- Versatile Reporting

...and more.



Light Element Analysis

AAF